Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/535,171	FUKUI ET AL.
Examiner	Art Unit
Huyen Le	3751

	SEARCHED			
Class	Subclass	Date	Examiner	
401	99 107-108	10/12/2006	HL	

ГИI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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